

Notice of References Cited	Application/Control No. 10/510,400		Applicant(s)/Patent Under Reexamination SHIONO ET AL.	
	Examiner Henok G. Heyi		Art Unit 2627	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,080,947 A	01-1992	Yamada et al.	428/64.4
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*	C	US-5,698,344 A	12-1997	Bai et al.	430/1
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	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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